January 2004

## FDC6036P

**FAIRCHILE** 

## P-Channel 1.8V Specified PowerTrench<sup>®</sup> MOSFET

## **General Description**

This dual P-Channel 1.8V specified MOSFET uses Fairchild's advanced low voltage PowerTrench process. Packaged in FLMP SSOT-6, the  $R_{DS(ON)}$  and thermal properties of the device are optimized for battery power management applications.

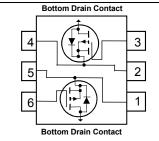
## Applications

- Battery management/Charger Application
- Load switch

## Features

- -5 A, -20 V.  $R_{DS(ON)} = 44 \text{ m}\Omega \textcircled{0} V_{GS} = -4.5 \text{ V}$  $R_{DS(ON)} = 64 \text{ m}\Omega \textcircled{0} V_{GS} = -2.5 \text{ V}$  $R_{DS(ON)} = 95 \text{ m}\Omega \textcircled{0} V_{GS} = -1.8 \text{ V}$
- Low gate charge, High Power and Current handling capability
- + High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- FLMP SSOT-6 package: Enhanced thermal performance in industry-standard package size



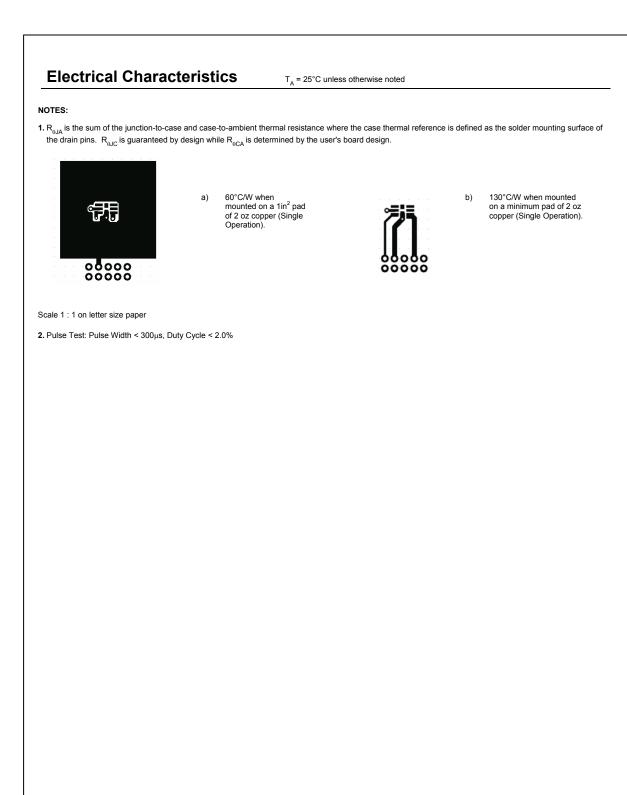


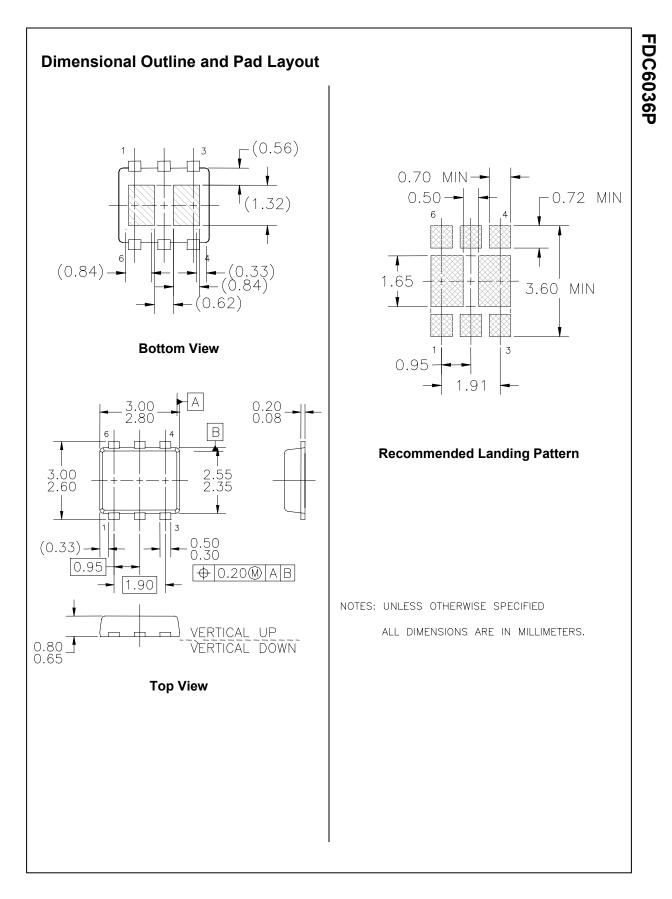
## MOSFET Maximum Ratings TA=25°C unless otherwise noted

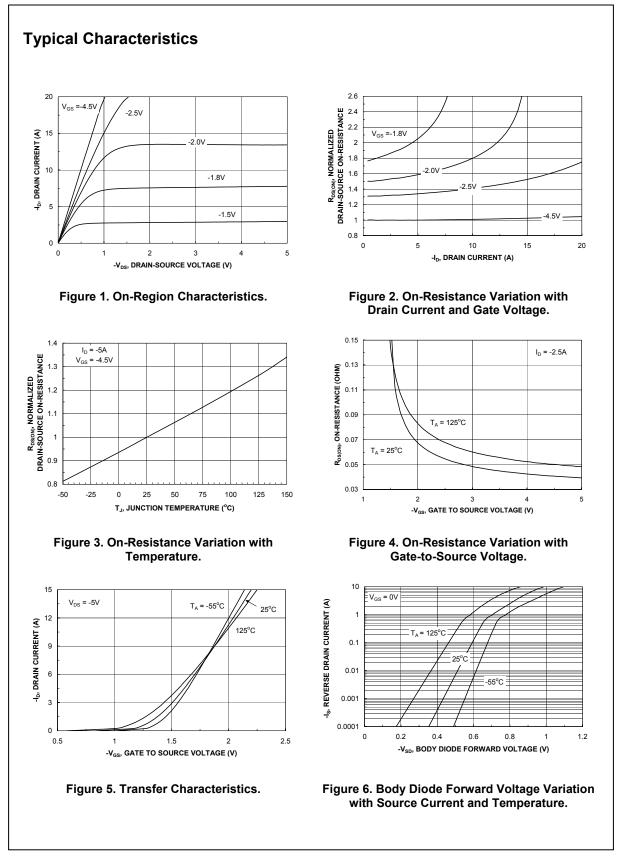
| Symbol  | Parameter   |             | Ratings     | Units      |
|---|---|-------------|-------------|------------|
| V <sub>DSS</sub>                                    | Drain-Source Voltage                              |             | -20         | V          |
| V <sub>GSS</sub>                                    | Gate-Source Voltage                               |             | ±8          | V          |
| I <sub>D</sub>                                      | Drain Current – Continuous                        | (Note 1a)   | -5          | А          |
|   | – Pulsed  |             | -20         |            |
| P <sub>D</sub> Power Dissipation for Dual Operation |   |             | 1.8         | W          |
|   | Power Dissipation for Single Operation            | (Note 1a)   | 1.8         |            |
|   |   | (Note 1b)   | 0.9         |            |
| T <sub>J</sub> , T <sub>stg</sub>                   | Operating and Storage Junction Tempera            | ature Range | -55 to +150 | °C         |
| Therma  | al Characteristics                                |             |             |            |
| $R_{\theta JA}$                                     | Thermal Resistance, Junction-to-Ambient (Note 1a) |             | 68          | °C/W       |
| R <sub>0JC</sub>                                    | Thermal Resistance, Junction-to-Case              |             | 1           |            |
|   | e Marking and Ordering Inf                        | ormation    |             |            |
| .036  | FDC6036P  | 7"          | 8mm         | 3000 units |

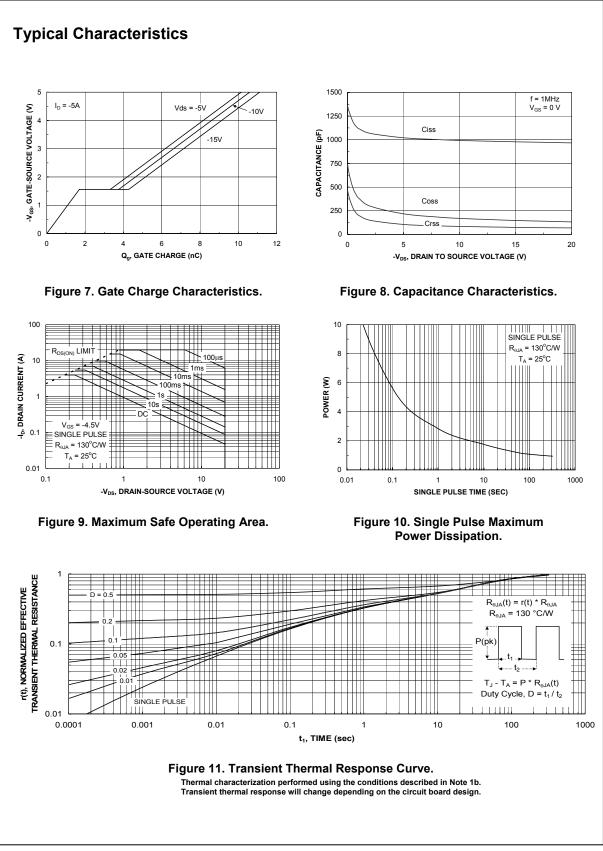
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| Symbol                                 | Parameter   | Test Conditions   | Min  | Тур                  | Max                  | Units |
|--|---|---|------|----------------------|----------------------|-------|
| Off Char                               | acteristics                                       |   |      |                      |                      |       |
| BV <sub>DSS</sub>                      | Drain–Source BreakdownVoltage                     | $V_{GS} = 0 V$ , $I_D = -250 \mu A$   | -20  |                      |                      | V     |
| <u>ΔBVdss</u><br>ΔT <sub>J</sub>       | Breakdown Voltage Temperature<br>Coefficient      | $I_D$ = –250 µA, Referenced to 25°C   |      | -24                  |                      | mV/°C |
| I <sub>DSS</sub>                       | Zero Gate Voltage Drain Current                   | $V_{\text{DS}} = -16 \text{ V},  V_{\text{GS}} = 0 \text{ V}$   |      |                      | -1                   | μA    |
| I <sub>GSS</sub>                       | Gate–Body Leakage                                 | $V_{GS} = \pm 8 V$ , $V_{DS} = 0 V$   |      |                      | ±100                 | nA    |
| On Char                                | acteristics (Note 2)                              |   |      |                      |                      |       |
| V <sub>GS(th)</sub>                    | Gate Threshold Voltage                            | $V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$  | -0.4 | -0.7                 | -1.5                 | V     |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate Threshold Voltage<br>Temperature Coefficient | $I_D$ = –250 $\mu$ A, Referenced to 25°C  |      | 4.4                  |                      | mV/°C |
| R <sub>DS(on)</sub>                    | Static Drain–Source<br>On–Resistance              | $ \begin{array}{l} V_{GS} = -4.5 \ V, \qquad I_D = -5.0 \ A \\ V_{GS} = -2.5 \ V, \qquad I_D = -4.0 \ A \\ V_{GS} = -1.8 \ V, \qquad I_D = -3.2 \ A \\ V_{GS} = -4.5 \ V, I_D = -5 \ A, T_J = 125^\circ C \end{array} $ |      | 37<br>52<br>74<br>51 | 44<br>64<br>95<br>61 | mΩ    |
| gfs                                    | Forward Transconductance                          | $V_{DS} = -5 V$ , $I_{D} = -5 A$  |      | 16                   |                      | S     |
| Dynamic                                | Characteristics                                   |   |      |                      |                      | •     |
| C <sub>iss</sub>                       | Input Capacitance                                 | $V_{DS} = -10 V$ , $V_{GS} = 0 V$ ,   |      | 992                  |                      | pF    |
| C <sub>oss</sub>                       | Output Capacitance                                | f = 1.0 MHz   |      | 169                  |                      | pF    |
| C <sub>rss</sub>                       | Reverse Transfer Capacitance                      |   |      | 85                   |                      | pF    |
| Rg                                     | Gate Resistance                                   | V <sub>GS</sub> = 15 mV f = 1.0 MHz   |      | 8.6                  |                      | mΩ    |
| Switchin                               | g Characteristics (Note 2)                        |   |      |                      | •                    |       |
| t <sub>d(on)</sub>                     | Turn–On Delay Time                                | $V_{DD} = -10 V$ , $I_D = -1 A$ ,   |      | 12                   | 24                   | ns    |
| tr                                     | Turn–On Rise Time                                 | $V_{GS}$ = -4.5 V, $R_{GEN}$ = 6 $\Omega$   |      | 10                   | 20                   | ns    |
| $t_{d(off)}$                           | Turn–Off Delay Time                               |   |      | 40                   | 64                   | ns    |
| t <sub>f</sub>                         | Turn–Off Fall Time                                |   |      | 20                   | 36                   | ns    |
| Q <sub>g</sub>                         | Total Gate Charge                                 | $V_{DS} = -10 V$ , $I_D = -5 A$ ,   |      | 10                   | 14                   | nC    |
| Q <sub>gs</sub>                        | Gate-Source Charge                                | V <sub>GS</sub> = -4.5 V  |      | 1.7                  |                      | nC    |
| Q <sub>gd</sub>                        | Gate-Drain Charge                                 |   |      | 2.0                  |                      | nC    |
| Drain-So                               | ource Diode Characteristics                       | and Maximum Ratings   |      |                      | •                    | •     |
| ls                                     | Maximum Continuous Drain-Sour                     | ce Diode Forward Current  |      |                      | -1.25                | Α     |
| V <sub>SD</sub>                        | Drain–Source Diode Forward<br>Voltage             | $V_{GS} = 0 V$ , $I_S = -1.25 A$ (Note 2)   |      | -0.7                 | -1.2                 | V     |
| trr                                    | Diode Reverse Recovery Time                       | I <sub>F</sub> = –5 A,  |      | 19                   |                      | ns    |
| Qrr                                    | Diode Reverse Recovery Charge                     | $d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$  |      | 7.8                  |                      | nC    |









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|---|--|---|---|
|---|--|---|---|

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